

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Inventor: Moshe FINAROV

U.S. Patent Application No. 09/626,793

Filed: July 26, 2000

: Confirmation No.8657

: Group Art Unit: 2851

: Examiner: David B. Esplin

For: APPARATUS FOR INTEGRATED MONITORING OF WAFERS AND FOR
PROCESS CONTROL IN THE SEMICONDUCTOR MANUFACTURING AND A
METHOD FOR USE THEREOF

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

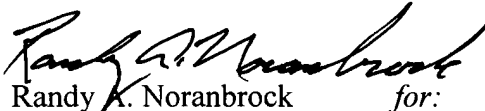
Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application and that the documents be made of record therein and appear among the "References Cited" on any patent to issue there from.

This Information Disclosure Statement is being filed under Rule 37 CFR 1.97(i), wherein applicants are submitting references before the grant of a patent to be placed in the file but not considered by the Patent Office. Accordingly, copies of the references as listed on the attached Form PTO-1449 are submitted herewith for placement in the file. No certification or fees are deemed necessary.

Respectfully submitted,

LOWE HAUPTMAN GILMAN & BERNER, LLP

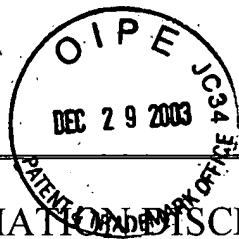


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INFORMATION DISCLOSURE
CITATION IN AN
APPLICATION
(PTO-1449)

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1268-093A

U.S. PATENT
APPLICATION NO.
09/626,793

APPLICANT
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FILING DATE
July 26, 2000

GROUP
2851

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	5,486,701	01/1996	Norton et al.			
	5,943,122	08/1999	Holmes			
	6,278,519	08/2001	Rosencwaig et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
	63104873 A	05/1988	Japan			Abstract	
	02098955 A	04/1990	Japan			Abstract	
	11264072 A	09/1999	Japan			Abstract	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.